


<b>Search Notes</b>  	<b>Application/Control No.</b>  10520310	<b>Applicant(s)/Patent Under Reexamination</b>  VAN DER MARK ET AL.
	<b>Examiner</b>  HENOK G HEYI	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
searched class 369/13.13, 13.17, 13.18, 13.19 and 13.33 - text search only (see search history printout) and also consulted primary Tan Dinh.	11/29/2007	HH
Updated search.	07/24/2008	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner